


<b>Search Notes</b> 	<b>Application/Control No.</b> 10724907	<b>Applicant(s)/Patent Under Reexamination</b> SEIVER, JOHN R.
	<b>Examiner</b> Kaplan, Hal I	<b>Art Unit</b> 2836

SEARCHED			
Class	Subclass	Date	Examiner
174	70B	8/23/2007	HK
174	71B	8/23/2007	HK
174	72B	8/23/2007	HK
174	99B	8/23/2007	HK
307	19	8/23/2007	HK
307	20	8/23/2007	HK
307	69	8/23/2007	HK
700	291	8/23/2007	HK

SEARCH NOTES		
Search Notes	Date	Examiner
62/612 (consulted William Doerrier)	9/4/2006	HK
174/70B,71B,72B,99B (consulted Chao Nguyen)	8/31/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	8/23/2007	HK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner